

## In-situ Growth of Epitaxial PbVO<sub>3</sub> Thin Films under Reduction Atmosphere

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PbVO<sub>3</sub> (PVO), a polar magnetic material considered as a candidate of multiferroic, has ferroelectricity along the c-axis and 2-dimensional antiferromagnetism lying in the in-plane through epitaxial growth [1,2]. PVO thin films were grown on LaAlO<sub>3</sub> (001) substrates under reduction atmosphere from a stable Pb<sub>2</sub>V<sub>2</sub>O<sub>7</sub> sintered target using pulsed laser deposition method. Epitaxial growth of the PVO films is possible only under Ar atmosphere with no oxygen partial pressure. X-ray diffraction was used to investigate the phase formation and texture of the films. We confirmed epitaxial growth of the PVO films with crystalline relationship of PbVO<sub>3</sub>[001]/LaAlO<sub>3</sub>[001] and PbVO<sub>3</sub>[100]/LaAlO<sub>3</sub>[100]. In addition, surface morphology of the films displays drastic changes in accordance with the growth conditions. Elongated PVO grains are related to the Pb<sub>2</sub>V<sub>2</sub>O<sub>7</sub> pyrochlore structure. The relation between structural deformation and ferroelectricity in the PVO films was examined by local measurement of piezoresponse force microscopy.

### References

- [1] A. A. Belik et al., Chem. Mater. 17, 269 (2005).  
[2] A. A. Tsirlin et al., Phys. Rev. B 77, 092402 (2008).

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## Synthesis and Characterization of Large-Area and Highly Crystalline Tungsten Disulphide (WS<sub>2</sub>) Atomic Layer by Chemical Vapor Deposition

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Transition metal dichalcogenides (MoS<sub>2</sub>, WS<sub>2</sub>, WSe<sub>2</sub>, MoSe<sub>2</sub>, NbS<sub>2</sub>, NbSe<sub>2</sub>, etc.) are layered materials that can exhibit semiconducting, metallic and even superconducting behavior. In the bulk form, the semiconducting phases (MoS<sub>2</sub>, WS<sub>2</sub>, WSe<sub>2</sub>, MoSe<sub>2</sub>) have an indirect band gap. Recently, these layered systems have attracted a great deal of attention mainly due to their complementary electronic properties when compared to other two-dimensional materials, such as graphene (a semimetal) and boron nitride (an insulator). However, these bulk properties could be significantly modified when the system becomes mono-layered; the indirect band gap becomes direct. Such changes in the band structure when reducing the thickness of a WS<sub>2</sub> film have important implications for the development of novel applications, such as valleytronics. In this work, we report for the controlled synthesis of large-area (~cm<sup>2</sup>) single-, bi-, and few-layer WS<sub>2</sub> using a two-step process. WO<sub>x</sub> thin films were deposited onto a Si/SiO<sub>2</sub> substrate, and these films were then sulfurized under vacuum in a second step occurring at high temperatures (750°C). Furthermore, we have developed an efficient route to transfer these WS<sub>2</sub> films onto different substrates, using concentrated HF. WS<sub>2</sub> films of different thicknesses have been analyzed by optical microscopy, Raman spectroscopy, and high-resolution transmission electron microscopy.

**Keywords:** Transition metal dichalcogenides, WS<sub>2</sub>